

13. TEST SETUP PHOTOGRAPHS

FCC ID: Samsung Electronics Co., Ltd.		HAC (T-COIL) TEST REPORT		Approved by: Quality Manager
Filename: 1M1712220333-05.A3L	Test Dates: 01/01/2018	DUT Type: Portable Handset		Page 41 of 43

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Figure 13-1
Test Setup for Wireless Device

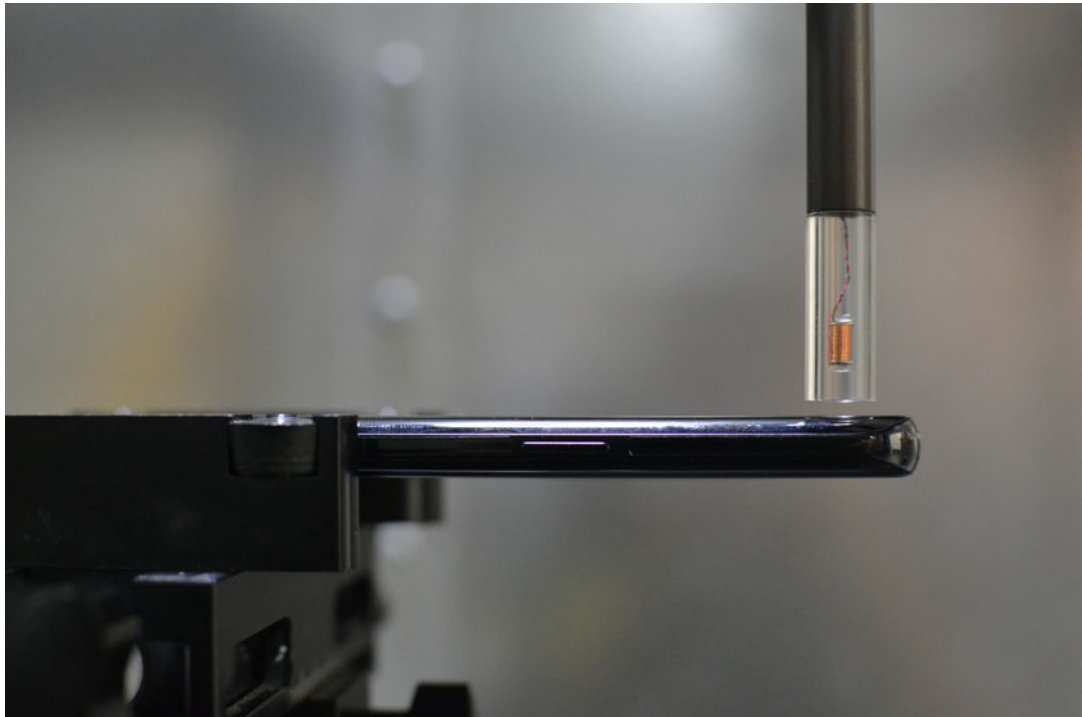


Figure 13-2
Test Setup for Wireless Device

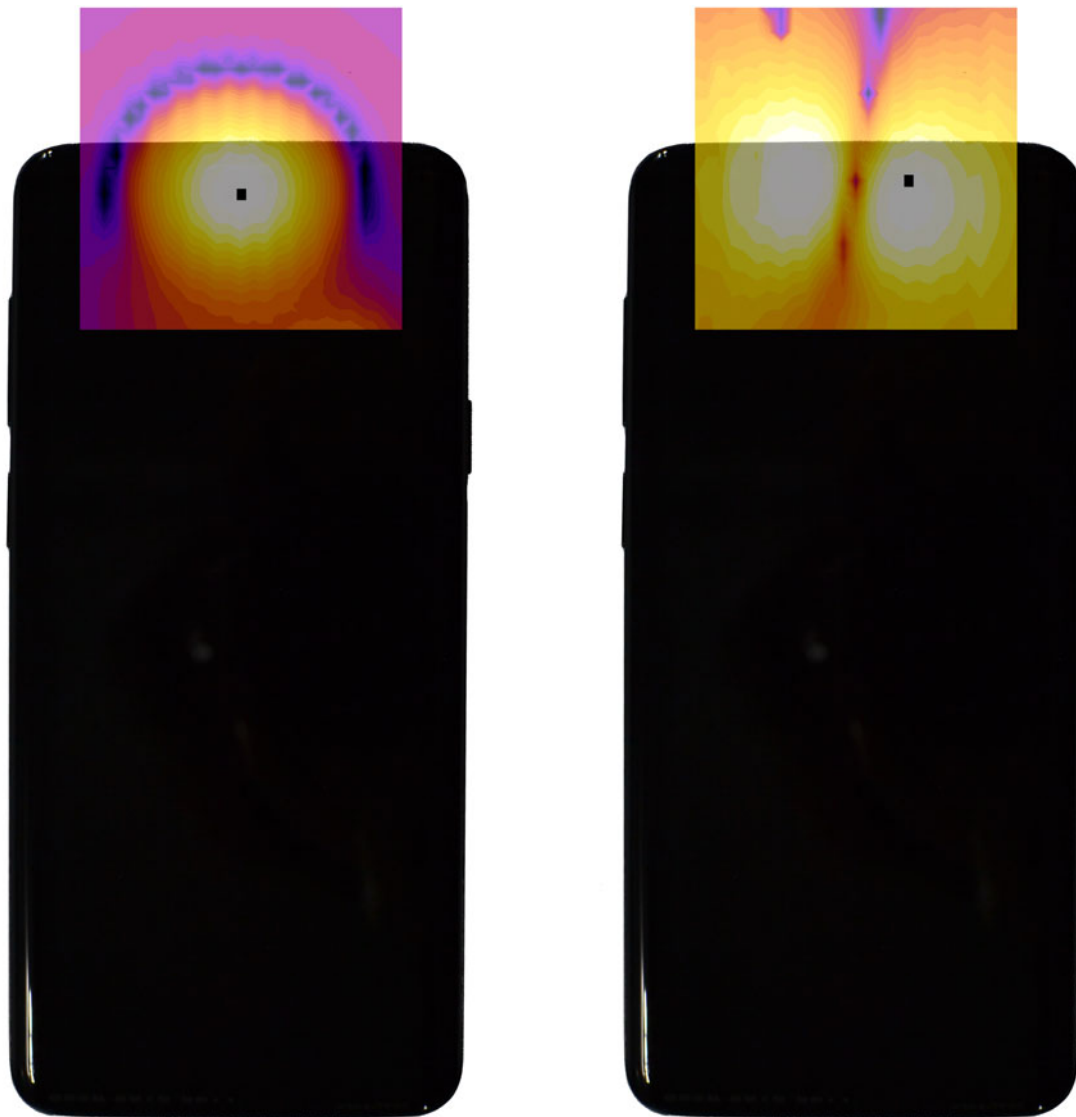
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Axial

Radial (Transverse)

Figure 13-3
T-Coil Scan Overlay Magnetic Field Distributions

Note: Final measurement locations are indicated by a cursor on the contour plots.

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